


<b>Search Notes</b>  	<b>Application/Control No.</b>  10574402	<b>Applicant(s)/Patent Under Reexamination</b>  RIEDER ET AL.
	<b>Examiner</b>  DAVID S BAKER	<b>Art Unit</b>  2884

SEARCHED			
Class	Subclass	Date	Examiner
250	338.1	07 DEC 08	DSB
250	339.11	07 DEC 08	DSB
250	339.14	07 DEC 08	DSB
250	341.8	07 DEC 08	DSB
250	342	07 DEC 08	DSB
250	339.02	07 DEC 08	DSB
250	349	07 DEC 08	DSB

SEARCH NOTES		
Search Notes	Date	Examiner
See attached EAST Search History	07 DEC 08	DSB
Consultation: Examiner Christine Sung AU 2884	07 DEC 08	DSB

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
ALL	ALL; Search Terms: "(infra\$red OR IR).clm. AND (matrix OR array OR grid).clm. AND maximum.clm. AND comparator.clm. diode.clm."	07 DEC 08	DSB
250	ALL; Search Terms: "(infra\$red OR IR).clm. AND (matrix OR array OR grid).clm. AND maximum.clm. AND comparator.clm. diode.clm."	07 DEC 08	DSB
ALL	ALL; Search Terms: "(infra\$red OR IR).clm. AND (matrix OR array OR grid).clm. AND maximum.clm. AND diode.clm."	07 DEC 08	DSB
250	ALL; Search Terms: "(infra\$red OR IR).clm. AND (matrix OR array OR grid).clm. AND maximum.clm. AND diode.clm."	07 DEC 08	DSB

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Examiner,Art Unit 2884